

CLAIMS IN CURRENT FORM

(IN FORMAT COMPLIANT WITH THE REVISED 37 CFR 1.121)

1. (PREVIOUSLY AMENDED) An apparatus comprising:

a low speed tester; and

a host emulator having (i) a first interface coupled to said low speed tester to receive a test vector at a first speed,  
5 (ii) a second interface configured to (a) transmit said test vector to a device at a second speed faster than said first speed and (b) receive a response from said device and (iii) a third interface to said low speed tester to transfer a signal based upon said response, wherein said apparatus is configured to allow said low  
10 speed tester to perform high speed tests of said device at said second speed.

2. (PREVIOUSLY AMENDED) The apparatus according to claim 1, wherein said host emulator is further configured to perform a verification of said device.

3. (ORIGINAL) The apparatus according to claim 1, wherein said device comprises a Universal Serial Bus (USB) device.

4. (PREVIOUSLY AMENDED) The apparatus according to claim 1, further comprising:

a test vector generator configured to transfer said test vector to said low speed tester.

5. (ORIGINAL) The apparatus according to claim 4, wherein said low speed tester is configured to control said host emulator.

6. (PREVIOUSLY AMENDED) The apparatus according to claim 4, wherein said low speed tester is configured in response to said test vector.

7. (PREVIOUSLY AMENDED) The apparatus according to claim 6, wherein said test vector generator is configured to generate said test vector.

8. (ORIGINAL) The apparatus according to claim 1, wherein said apparatus is further configured to test a reception and transmission operation of said device.

9. (ORIGINAL) The apparatus according to claim 1, wherein said apparatus is further configured to initiate one or more test packets.

10. (ORIGINAL) The apparatus according to claim 9, wherein said device is further configured to receive and verify said one or more test packets.

11. (PREVIOUSLY AMENDED) The apparatus according to claim 1, wherein said device is further configured to transmit one or more test packets.

12. (PREVIOUSLY AMENDED) The apparatus according to claim 11, wherein said host emulator is further configured to receive and verify said one or more test packets.

13. (ORIGINAL) The apparatus according to claim 1, wherein said low speed tester is further configured to generate a pass/fail signal.

14. (ORIGINAL) The apparatus according to claim 1, wherein said apparatus is configured to perform at least one test of a plurality of test modes wherein said plurality of test modes comprise USB 2.0 defined test modes for use in a production test environment.

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15. (PREVIOUSLY AMENDED) An apparatus comprising:

means for transferring a test vector at a first speed to  
a first interface;

5 means for transmitting said test vector from a second  
interface to a device at a second speed faster than said first  
speed;

means for receiving a response from said device at said  
second interface; and

10 means for transferring a signal based upon said response  
from a third interface to perform high speed tests of said device  
at said second speed.

16. (PREVIOUSLY AMENDED) A method for testing comprising  
the steps of:

(A) transferring a test vector at a first speed from a  
low speed tester to a first interface of a host emulator;

5 (B) transmitting said test vector from a second  
interface of said host emulator at a second speed faster than said  
first speed to a device;

(C) receiving a response from said device at said second  
interface; and

10 (D) transferring a signal from a third interface of said  
host emulator to said low speed tester based upon said response to  
perform high speed tests of said device at said second speed.

17. (PREVIOUSLY AMENDED) The method according to claim 16, wherein said device comprises a USB device.

18. (PREVIOUSLY AMENDED) The method according to claim 16, further comprising the step of:

configuring said low speed tester to control said host emulator.

19. (PREVIOUSLY AMENDED) The method according to claim 18, further comprising the step of:

generating said test vector external to said host emulator.

20. (ORIGINAL) The method according to claim 16, further comprising performing at least one of a plurality of test modes wherein the plurality of test modes comprise USB 2.0 defined test modes for use in a production test environment.